



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
United States Patent and Trademark Office
Address: COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, Virginia 22313-1450
www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/615,880	07/10/2003	Sabera Kazi	H0004522	8476
7590	12/13/2007			
Matthew S. Luxton Honeywell International, Inc. 101 Columbia Road, Law Dept AB2 Morristown, NJ 07962			EXAMINER VLAHOS, SOPHIA	
			ART UNIT 2611	PAPER NUMBER
			MAIL DATE 12/13/2007	DELIVERY MODE PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary	Application No.	Applicant(s)
	10/615,880	KAZI ET AL.
	Examiner	Art Unit
	SOPHIA VLAHOS	2611

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --
Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) Responsive to communication(s) filed on 24 October 2007.
- 2a) This action is FINAL. 2b) This action is non-final.
- 3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) Claim(s) 1-3 and 5-21 is/are pending in the application.
 - 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) Claim(s) _____ is/are allowed.
- 6) Claim(s) 1-3 and 5-21 is/are rejected.
- 7) Claim(s) _____ is/are objected to.
- 8) Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) The specification is objected to by the Examiner.
- 10) The drawing(s) filed on 24 October 2007 is/are: a) accepted or b) objected to by the Examiner.

Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).

Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
 - a) All b) Some * c) None of:
 1. Certified copies of the priority documents have been received.
 2. Certified copies of the priority documents have been received in Application No. _____.
 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- 1) Notice of References Cited (PTO-892)
- 2) Notice of Draftsperson's Patent Drawing Review (PTO-948)
- 3) Information Disclosure Statement(s) (PTO/SB/08)
Paper No(s)/Mail Date _____
- 4) Interview Summary (PTO-413)
Paper No(s)/Mail Date. _____
- 5) Notice of Informal Patent Application
- 6) Other: _____

Art Unit: 2611

DETAILED ACTION

Drawings

1. The drawings (Fig. 2, Fig. 3, Fig. 4) were received on 10/24/2007. These drawings are acceptable.

Allowable Subject Matter

2. The indicated allowability of claims 4, 10, 17 is withdrawn based on a broader interpretation of the claimed limitation "sample interval" (which in the claim is not specified as being less than a symbol interval).

Claim Rejections - 35 USC § 103

3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

4. Claims 1-3, 5, 7 are rejected under 35 U.S.C. 103(a) as being obvious over Boccuzzi et. al. (U.S. 5,786,725) in view of Chung et. al. (U.S. 2004/0190655) and Applicant's admitted prior art of the instant application (hereafter referred to as AAPA).

With respect to claim 1, Boccuzzi et. al., disclose: means for converting the input signal to in-phase and quadrature components (not shown, but see Fig. 1A, and Fig. 1B, DQPSK transmitter and receiver where it is understood that the I and Q signal are

Art Unit: 2611

combined to be transmitted over the communication medium, and at the receiver I and Q signals are separated into I and Q signals); a differential demodulator to determine a demodulated phase by comparing the in-phase and quadrature components of the input signal with a first delayed, conjugated version of the in-phase and quadrature components of the input signal (see Fig. 2, differential detector, see column 2, lines 14-16, 27-41); and a symbol mapping circuit to map the phase to an output symbol, comprising one or more bits of data (see column 1, table 1 and column 2, lines 42-49 for the symbol mapping based on the detected phase shift).

Boccuzzi et. al., do not disclose: a frequency offset calculation circuit to determine a frequency offset between an oscillator in the DPSK receiver and an oscillator in the DPSK transmitter by comparing the in-phase and quadrature components of the input signal with a second delayed, conjugated version of the in-phase and quadrature components of the input signal; wherein the delay associated with the second delayed, conjugated version of the in-phase and quadrature components of the input signal is approximately one sample interval; a frequency correction circuit to correct the demodulated phase using the frequency offset into a corrected phase; a phase correction circuit to determine an absolute phase using the corrected phase;

In the same filed of endeavor, Chung et al., disclose: a frequency offset calculation circuit (see first sentence of paragraph [0004] and Fig. 1) to determine a frequency offset between an oscillator in the DPSK receiver and an oscillator in the DPSK transmitter by comparing the in-phase and quadrature components of the input

signal with a second delayed, conjugated version of the in-phase and quadrature components of the input signal; wherein the delay associated with the second delayed, conjugated version of the in-phase and quadrature components of the input signal is approximately one sample interval; (see paragraph [0005] see delay is equal to a symbol interval corresponding to the claimed sample interval and Fig. 1 operation inside box 40 performed on symbols (the are the in-phase and quadrature components) and see estimation of $\Delta\theta$ phase rotation caused by the carrier offset).

Therefore at the time of the invention, it would have been obvious to a person of ordinary skill in the art to modify the system of Boccuzzi et. al., so that it includes the frequency offset determination circuit of Chung et. al., since phase errors introduced by carrier offset cause symbol phase rotation in differential demodulations (differential PSK, BPSK, QPSK) therefore the phase rotation caused by the frequency offset has to be known so that demodulation errors are avoided.

The AAPA discloses: a frequency correction circuit to correct the demodulated phase using the frequency offset into a corrected phase (see Fig. 2 of the instant application, adder 223 adding the phase error corresponding to the frequency offset to the phase determined from the differential demodulator); determining an absolute phase; and a symbol mapping circuit to map the absolute phase to an output symbol, comprising one or more bits of data [see last sentence of paragraph [0008]].

At the time of the invention, it would have been obvious to a person of ordinary skill in the art to modify the system of Boccuzzi and Chung, so that the phase rotation estimate (caused by the frequency (carrier) offset) is added to the phase determined by

the differential demodulator so that a phase that is compensated for carrier offset is obtained. Also, it would have been obvious to a person of ordinary skill in the art to modify the system of Boccuzzi and Chung so that it includes a phase correction circuit that determines an absolute phase using the corrected phase so that it can be mapped to symbols and corresponding bits (AAPA, paragraph [0008]).

With respect to claim 2, Chung et. al., discloses: removing noise and glitches caused by phase transients between symbols, see squaring operation of element 20 of Fig. 1, and second half of paragraph [0005] and all of paragraphs [0006]-[0007], where the squared phasor (that includes the frequency offset) that is insensitive to phase differences between successive modulated samples (understood to also include phase errors (transients) caused for example by non-ideal components), and see that the noise can be ignored).

With respect to claim 3, Boccuzzi et. al., disclose: wherein the delay associated with the first delayed version of the in-phase and quadrature components of the input signal in the differential demodulator is approximately one symbol interval (column 2, lines 22-26, see that T_s is one symbol interval).

With respect to claim 5, all of the limitations of claim 1 are analyzed above in claim 1 and the AAPA discloses: further comprising an optimal sample calculation circuit to determine an optimal sample to use to determine the demodulated phase and the

frequency offset (see Fig. 2, elements 210, 212, 214, and the control of switches 208 and 216 see paragraphs [0008]-[0010] of the specification).

With respect to claim 7, all of the limitations of claim 7 are analyzed above in claim 5, and claim 7 is analyzed similarly to claim 2 above.

5. Claim 6 is rejected under 35 U.S.C. 103(a) as being obvious over Boccuzzi et. al. (U.S. 5,786,725) in view of Chung et. al. (U.S. 2004/0190655), Applicant's admitted prior art of the instant application (hereafter referred to as AAPA) and Legrand et. al., (U.S. 6,674,822).

With respect to claim 6, neither Boccuzzi et. al., nor Chung, or AAPA disclose: wherein the optimal sample calculation circuit determines the optimal sample as the sample associated with a peak amplitude of the combined in-phase and quadrature components of each sample in each symbol interval.

In the same field of endeavor, Legrand et. al., disclose: wherein the optimal sample calculation circuit determines the optimal sample as the sample associated with a peak amplitude each sample in each symbol interval (see column 1, lines 62-67, column 2, lines 7, column 3, lines 40-42, where the sample (and subsequently the sampling instant) with the maximum value is determined and keeps updating). At the time of the invention, it would have been obvious to a person skilled in the art at the time of the invention, to use the teachings of Legrand in the system of Boccuzzi , to determine the optimal sample as the sample associated with a peak amplitude

Art Unit: 2611

(maximum value) of the combined in-phase and quadrature components of each sample in each symbol interval. The benefit of using the teachings of Legrand et. al., in the system of the Bocuzzi (to perform best sample selection) include: limiting the number of computations and operating costs (see column 1, lines 49-51 of Legrand et. al.,)

6. Claims 1-3, 5 7-12, 14-16, 18-19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hendrickson et. al., (U.S. 6,055,281) in view of Chung et. al., (U.S. 2004/019655) and Applicant's admitted prior art of the instant application (hereafter referred to as AAPA).

With respect to claim 1, Hendrickson et. al., disclose: means for converting the input signal to in-phase and quadrature components (see Fig. 2, and Fig. 3A showing details of block 210, see I and Q components out of mixers 306 and 308, column 7, lines 34-40, column 10, lines 33-39); a differential demodulator to determine a demodulated phase by comparing the in-phase and quadrature components of the input signal with a first delayed, conjugated version of the in-phase and quadrature components of the input signal (Fig. 2 block 212 Differential decoder, details of which are shown in Figure 4a, see column 16, lines 4-34); a symbol mapping circuit to map the absolute phase to an output symbol, comprising one or more bits of data (Fig. 2, block I214, slicer, see column 17, lines 16-44, see table 2 where absolute values of the phase (Im) component are mapped into an output code).

Hendrickson et. al., do not expressly teach: a frequency offset calculation circuit

Art Unit: 2611

to determine a frequency offset between an oscillator in the DPSK receiver and an oscillator in the DPSK transmitter by comparing the in-phase and quadrature components of the input signal with a second delayed, conjugated version of the in-phase and quadrature components of the input signal; wherein the delay associated with the second delayed, conjugated version of the in-phase and quadrature components of the input signal is approximately one sample interval; a frequency correction circuit to correct the demodulated phase using the frequency offset into a corrected phase; a phase correction circuit to determine an absolute phase using the corrected phase;

In the same filed of endeavor, Chung et al., disclose: a frequency offset calculation circuit (see first sentence of paragraph [0004] and Fig. 1) to determine a frequency offset between an oscillator in the DPSK receiver and an oscillator in the DPSK transmitter by comparing the in-phase and quadrature components of the input signal with a second delayed, conjugated version of the in-phase and quadrature components of the input signal; wherein the delay associated with the second delayed, conjugated version of the in-phase and quadrature components of the input signal is approximately one sample interval (see paragraph [0005] and Fig. 1 operation inside box 40 performed on symbols (the are the in-phase and quadrature components) and see estimation of $\Delta\theta$ phase rotation caused by the carrier offset, where the symbol interval delay of Chung et. al., correspond to the claimed sample interval).

Therefore at the time of the invention, it would have been obvious to a person of ordinary skill in the art to modify the system of Hendrickson et. al., so that it includes

the frequency offset determination circuit of Chung et. al., since phase errors introduced by carrier offset cause symbol rotation in differential demodulations (differential PSK, BPSK, QPSK) therefore the phase rotation caused by the frequency offset has to be known so that demodulation errors are avoided.

Applicant's admitted prior art discloses: a frequency correction circuit to correct the demodulated phase using the frequency offset into a corrected phase (Fig. 2, adder 223, adds the phase offset corresponding to the frequency offset to the phase out of the differential demodulator).

At the time of the invention, it would have been obvious to a person of ordinary skill in the art to modify the system of Hendrickson et. al., and Chung et. al., based on the teachings of AAPA, so that the phase rotation caused by the frequency offset (as taught by Chung) is added to the phase out of the differential decoder of Hendrickson et. al., so that the phase offset rotation is accounted for. With respect to the limitation, "a phase correction circuit to determine an absolute phase using the corrected phase;" see that in the system of Hendrickson et. al., modified by Chung and AAPA, the slicer takes an absolute value of the phase of the frequency-offset corrected phase.

With respect to claim 2, Chung et. al., discloses: removing noise and glitches caused by phase transients between symbols, see squaring operation of element 20 of Fig. 1, and second half of paragraph [0005] and all of paragraphs [0006]-[0007], where the squared phasor (that includes the frequency offset) that is insensitive to phase differences between successive modulated samples (understood to also include phase

errors (transients) caused for example by non-ideal components), and see that the noise can be ignored).

With respect to claim 3, Hendrickson et. al., disclose: wherein the delay associated with the first delayed version of the in-phase and quadrature components of the input signal in the differential demodulator is approximately one symbol interval (see Fig. 4a, delay, column 16, lines 20-34 where in equation (10) is the product of symbol k and the conjugated version of symbol k-1, i.e. delay 403 has a duration of approximately one symbol interval).

With respect to claim 5, all of the limitations of claim 1 are analyzed above in claim 1 and the AAPA discloses: further comprising an optimal sample calculation circuit to determine an optimal sample to use to determine the demodulated phase and the frequency offset (see Fig. 2, elements 210, 212, 214, and the control of switches 208 and 216 see paragraphs [0008]-[0010] of the specification).

With respect to claim 7, all of the limitations of claim 7 are rejected above in claim 5, and claim 7 is rejected based on a rationale similar to the one used to reject claim 2 above.

With respect to claim 8,10 claims 8, 10 are rejected based on a rationale similar to the one used to reject claim 1 above. With respect to the limitations "digitizing the

Art Unit: 2611

DPSK input signal" see Hendrickson et. al., (column 10, line 33, 45-47, conversion of signal 159 to digital logic levels) and "filtering the I and Q components of the DSPK input signal to remove noise" see Fig. 3A; integrate and dump filters 310 of Hendrickson et. al.,)

With respect to claims 9, 11-12, 14 these claims are rejected based on a rationale similar to the one used to reject claims 3,2,5, 7 respectively above..

With respect to claims 15-19 these claims are rejected based on rationale similar to the one used to reject claims 8-12 respectively.

7. Claims 6, 13, 20-21 are rejected under 35 U.S.C. 103(a) as being unpatentable over Hendrickson et. al., (U.S. 6,055,281) in view of Chung et. al., (U.S. 2004/019655), Applicant's admitted prior art of the instant application (hereafter referred to as AAPA), and Legrand et. al. (U.S. 6,674,822).

With respect to claim 6, neither Hendrickson et. al., nor Chung, or AAPA disclose: wherein the optimal sample calculation circuit determines the optimal sample as the sample associated with a peak amplitude of the combined in-phase and quadrature components of each sample in each symbol interval.

In the same field of endeavor, Legrand et. al., disclose: wherein the optimal sample calculation circuit determines the optimal sample as the sample associated with a peak amplitude each sample in each symbol interval (see column 1, lines 62-67,

column 2, lines 7, column 3, lines 40-42, where the sample (and subsequently the sampling instant) with the maximum value is determined and keeps updating). At the time of the invention, it would have been obvious to a person skilled in the art at the time of the invention, to use the teachings of Legrand in the system of Hendrickson et. al., to determine the optimal sample as the sample associated with a peak amplitude (maximum value) of the combined in-phase and quadrature components of each sample in each symbol interval. The benefit of using the teachings of Legrand et. al., in the system of the Hendrickson et. al., (to perform best sample selection) include: limiting the number of computations and operating costs (see column 1, lines 49-51 of Legrand et. al.,)

With respect to claims 13, 20 these claims are rejected based on a rationale similar to the one used to reject claim 6 above.

With respect to claim 21, Hendrickson et. al., disclose: further comprising means for removing glitches caused by phase transients between symbols (see Fig.3A, integrated and dump filters for I and Q components).

Conclusion

8. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

Kim (U.S. 7,058,1151)

Dick et. al., (U.S. 7,103,027)

Chung et. al., (U.S. 7,164,731)

Huang et. al., (U.S. 5,991,289)

Tsuda et. al., (U.S. 5,313,493)

LaBerge et. al., (U.S. 5,142,287)

Contact Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to SOPHIA VLAHOS whose telephone number is 571 272 5507. The examiner can normally be reached on MTWRF 8:30-17:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mohammed Ghayour can be reached on 571 272 3021. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 2611

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

SV
12/03/2007


CHIEH M. FAN
SUPERVISORY PATENT EXAMINER